

Code No: R18A0418

(Autonomous Institution – UGC, Govt. of India)

IV B.Tech I Semester Supplementary Examinations, April 2023

VLSI Design

(ECE)												
Roll No												

Time: 3 hours

Max. Marks: 70

Note: This question paper Consists of 5 Sections. Answer **FIVE** Questions, Choosing ONE Question from each SECTION and each Question carries 14 marks.

SECTION-I

1	A	With neat sketches explain the CMOS n-well fabrication process indicating [the masks used.			
	B	Discuss various forms of pull-up with neat diagrams. OR	[7M]		
2	A	Derive an equation for I_{DS} Vs V_{DS} of an n-channel Enhancement MOSFET.	[7M]		
_	B	Explain the operations of CMOS inverter in various regions.	[7M]		
		SECTION-II			
3	\boldsymbol{A}	Tabulate the encoding scheme for a simple single metal nMOS process with			
		respect to various MOS layers.			
	B	Explain lambda based design rules of CMOS / BiCMOS	[7M]		
		OR			
4	A	Draw the flow chart of VLSI Design flow and explain the operation of each step in detail.	[7M]		
	В	What is stick diagram and explain about different symbols used for components in Stick diagram. Draw the stick and layout for a two input CMOS NAND gate.	[7M]		
		SECTION-III			
5	\boldsymbol{A}	Explain dynamic CMOS logic and give its advantages and disadvantages	[7 M]		
	B	Derive the expression for time delay Tsd in case of MOSFET.	[7M]		
		OR			
6	A	Explain clocked CMOS logic and n-p CMOS logic. Mention their advantages and disadvantages.	[7M]		
	B	Discuss about the choice of fan – in and fan – out selection in gate level design	[7M]		
		SECTION-IV			
7	\boldsymbol{A}	Design a comparator using XNOR gates?	[7M]		
	B	Write a note on the different Parameters influencing low power design	[7M]		
		OR			
8	A	Draw the basic block diagram of 4-bit adder and explain its operation in detail.	[8M]		
	В	What is CPLD? Draw its basic structure and give its applications. <u>SECTION-V</u>	[6M]		
9	\boldsymbol{A}	Explain system-level test techniques.	[7M]		
	B	Explain about memory-self test with the help of a schematic.	[7M]		

- Explain built in self-test technique. Explain fault models. 10 A
 - B
